



UPDATE CHANGE NOTIFICATION # 16674Generic Copy

Issue Date: 14-Sep-2011**TITLE:** Update Notification to Previously Issued PCN #16674 - Additional Devices**PROPOSED FIRST SHIP DATE:** 14-Dec-2011**AFFECTED CHANGE CATEGORY(S):** ON Semiconductor Fab Site**ADDITIONAL RELIABILITY DATA:** AvailableContact your local ON Semiconductor Sales Office or Laura Rivers<laura.rivers@onsemi.com>**SAMPLES:** Contact your local ON Semiconductor Sales Office**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**Contact your local ON Semiconductor Sales Office or Masitah Aznam<masitah.aznam@onsemi.com>**NOTIFICATION TYPE:**

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

ON Semiconductor is notifying customers of this update notification to a previous issued FPCN#16674. The only updated information is addition of 2 devices, NSR02F30NXT5G and NSR01F30NXT5G at list of affected parts.

Original FPCN#16674 is as below:

ON Semiconductor is notifying customers of its plan to transfer Small Signal Schottky in DSN2 0201 CSP package from ON Semiconductor ZR Fab in Phoenix (USA) to ON Semiconductor ISMF Fab in Seremban (Malaysia).

The ISMF facility is an ON Semiconductor owned wafer fab that has been producing products for ON Semiconductor since 1998. Several existing technologies within ON Semiconductor's product families are currently sourced from ISMF, including Zener, Diodes, Small Signal Transistor, and USB array filter products. ON Semiconductor Seremban Wafer FAB is an internal factory that is TS16949, ISO-9001 and ISO-14000 certified.



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RELIABILITY DATA SUMMARY:

Reliability Test Results:

Package: DSN2 0201 CSP
Qual Vehicle: NSR02L30NXT5G

Test:	Conditions:	Interval:	Results
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/240
TC+PC	Ta= -40C to 125 C	500 cyc	0/240
HTRB	Tj=150C,80% Rated Voltage	1008 hrs	0/240
IOL	Ta=25C, delta Tj=100C Ton=Toff=2min	7500 cyc	0/240

Package: DSN2 0201 CSP
Qual Vehicle: NSR02F30NXT5G

Test:	Conditions:	Interval:	Results
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/240
TC+PC	Ta= -40C to 125 C	1000 cyc	0/240
HTRB	Tj= 125C,80% Rated Voltage	504 hrs	0/240
IOL	Ta=25C, delta Tj=100C Ton=Toff=2min	7500 cyc	0/240

ELECTRICAL CHARACTERISTIC SUMMARY:

Available upon request

CHANGED PART IDENTIFICATION:

Affected products from ON Semiconductor with date code 1141 representing WW41, 2011 and greater may be sourced from either the ISMF Fab in Seremban (Malaysia) or the ZR Fab in Phoenix (USA).

List of affected General Parts:

NSR02F30NXT5G
 NSR01F30NXT5G